disagrees with a mass spectrometric estimate⁸ of the relative bond strengths of OF and OF₂, it agrees in general with two other theoretical estimates.^{9,10} It also agrees in principal with the comparison made by Porter^{3a} between Cl₂O and the ClO radical in which he points out "the influence of the odd electron in strengthening the bond." In the case of the Cl–O bond energy, the increase is 16 kcal./mole over the average Cl–O bond energy in Cl₂O. In view of this and the relative position of the OF radical absorption, it appears not too

unlikely that the OF radical bond energy will be close to Glockler's first estimate⁹ of about 56 kcal./mole. It would seem then that the inability to find the OF radical in past gas phase work may be related to extreme chemical reactivity rather than to instability.

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Sulfur–Nitrogen and Oxygen–Nitrogen Bond Dissociation Energies of Some N-Fluorinated Amines

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The mass spectra and appearance potentials for the principal ions of FSO_2NF_2 , $(FSO_2)_2NF$, SF_5NF_2 , and FSO_2ONF_2 were measured. The values for D(S-N) were found to be 39, 48, and 32 kcal./mole, respectively, and D(O-N) for the latter compound was found to be 35 kcal./mole.

Introduction

A number of compounds containing sulfur, nitrogen, and fluorine have been reported.¹ However, until recently, no single bonded S–N or O–N N-fluorinated amines were known. The preparation of fluorosulfuryldifluoramine, FSO_2NF_2 ,² bis(fluorosulfuryl)fluoramine, $(FSO_2)_2NF$,³ pentafluorosulfur difluoramine, SF_5NF_2 ,⁴⁻⁶ and N,N-difluorohydroxylamine O-fluorosulfate, FSO_2ONF_2 ,⁷ made it of interest to investigate the mass spectra and appearance potentials of the principal ions in these compounds to determine the S–N and O–N bond dissociation energies.

Experimental

The compounds were prepared by the methods reported in the literature.²⁻⁷ Samples were purified by vacuum line fractionation followed by gas partition chromatography except for the FSO_2NF_2 . It was purified only by the literature method³ and was found to contain 4-5% SO₂. The FSO_2ONF_2 contained only a trace of SiF₄ and the $(FSO_2)_2NF$ and SF_5NF_2 showed

no impurities. Gas chromatographic, infrared, and mass spectral analyses were used for detection of impurities. The impurities found are not closely related to the compounds studied and are unlikely to cause interference with the appearance potential measurements. The shape of the ion efficiency curves did not indicate interferences. The mass spectra and appearance potentials were measured using a Consolidated Systems Corporation high speed mass spectrometer. All mass spectra were obtained at an ionization voltage of 70 v. The appearance potentials were obtained by the vanishing current method with argon added as a voltage standard. The repeller voltage was adjusted to its minimum value, the accelerator voltage was maintained constant, and magnetic scanning was used to keep the effects of contact potentials and field penetration the same during measurements. The mass spectra are shown in Table I and the appearance potentials (A.P.) in Table II. The errors shown for the appearance potentials are the estimated errors in the measurements. Table III shows the bond energies and heats of formation with the estimated error in the heats of formation.

Results and Discussion

The mass spectra obtained for these compounds are given in Table I. The mass spectrum for SF_5NF_2 differs from that reported by Cady and co-workers,⁴ but it is very similar to that reported by Logothetis, *et al.*⁵ The reason for this difference is not readily apparent but may be a result of the mass spectrometer source heater being turned off in this research, whereas the source heater was set at 175° when the former group recorded their spectrum.⁸ The heated source may cause sample decomposition.⁴ Samples generally gave more reproducible spectra if the source was unheated.

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Table I. Mass Spectra^a

			FSO ₂ -	(FSO ₂) ₂ -	FSO ₂ -
m/e	Ion ^b	SF_5NF_2	NF_2	NF	ONF_2
14	N ⁺		1.1		2.1
16	O+		1.2		0.7
19	F ⁺	1.1	0.6		0.6
20	HF ⁺	0.4	0.8		0.9
30	NO ⁺				25.8
32	S+	5.4	5.1		2.8
33	NF^+	3.4	11.2	0.1	14.8
34	i	0.2	• • •		• . •
35	$SF_{2^{2+}}$	0.4			
46	SN+	0.9	• • • •	1.9	
48	SO+		7.6	6.6	4.6
50	i	• • •	0.2	• • • •	• • •
51	SF ⁺	5.3	1.7	0.1	
52	NF_{2}^{+}	20.8	12.0	• • •	100.0
53	i	0.3	• • •		
54	SF4 ²⁺	0.8	• • •	• • • •	
64	SO_2^+	• • •	9.6	4.4	3.4
67	SOF ⁺	• • •	25.0	17.0	3.1
68	ONF_{2}^{+}	• • •		• • •	1.1
69	i		1.1	•	0.2
70	SF_2^+	8.3	• • •		• • •
72	1	0.4	• • •	• • •	
80	SO ₃ +	•	100.0	100.0	3.9
83	FSO_2^+	•••	100.0	100.0	28.0
85	i SF +	100.0	4.8	5.4	1.5
89	SF ₃ +	100.0 4.0	• • •	• • •	• • •
91	i ESO N+		0.2	8.2	• • •
97 90	FSO₂N ⁺		0.2	0.2 0.5	1.0
99 108	FSO ₃ +, i	12.5	• • •	0.5	1.0
	SF_4^+	0.5	• • •	• • •	• • •
110 116	i FSO₂NF+	0.5	0.1	• • •	• • •
127	SF_5^+	50.7		• • •	• • •
127	i sr	1.9	• • •		• • •
135	FSO ₂ NF ₂ ⁺	1.9	0.1		• • •
199	$(FSO_2)_2NF^+$	• • •		1.2	
177	(1002)2111	· · ·		<u> </u>	

^a Spectra obtained with 70-v. electrons. ^b The letter i signifies the ³⁴S isotope of the immediately preceding sulfur-containing entry.

potentials and assumed processes given in Table II. The ions and radicals are assumed to be formed in their ground states and to have no excess kinetic energy. The work of Reese, Diebler, and Franklin⁹ on sulfuryl fluoride, SO_2F_2 , gives an ionization potential I.P. (FSO₂) = 11.4 e.v. and $\Delta H_f(FSO_2^+) = 5.3$ e.v. Using these values the S-N bond energy for FSO₂NF₂ is calculated to be 39 kcal./mole and that for (FSO₂)₂NF to be 48 kcal./mole, and the heat of formation of FSO₂NF₂ is -170 kcal./mole.

The S–N bond dissociation energy for SF_5NF_2 can be calculated from the appearance potential for the NF_2^+ ion from the relation

$$D(S-N) = A.P.(NF_{2}^{+}) - I.P.(NF_{2}) - D(S-F)$$

The S-F bond energy is 3.1 e.v. from the heat of formation of SF₆^{10a} and the ionization potential of NF₂ is 11.8 e.v.^{10b} This gives D(S-N) = 16.3 - 11.8- 3.1 = 1.4 e.v. = 32 kcal./mole. A value of $\Delta H_{\rm f}$ -(SF₅NF₂) = 10.8 e.v. or -249 kcal./mole was obtained using the known $\Delta H_{\rm f}$ (SF₄) = -171.7 kcal./mole,¹¹ $\Delta H_{\rm f}$ (NF₂⁺) = 12.2 e.v.,^{10b} and $\Delta H_{\rm f}$ (F) = 18.5 kcal./mole.^{10a}

The ionization efficiency curve for the SF_5^+ ion from SF_5NF_2 has a long tail and appears to be due to two different processes, one with an appearance potential at 12.0 v. and another at 14.3 v. The higher appearance potential was obtained by the linear extrapolation method. Diebler and Mohler¹² report the appearance potential of SF_5^+ from SF_6 to be 15.9 e.v. Fox and Curran¹³ report 15.85 e.v., and Marriott and Craggs¹⁴ report a value of 15.77 e.v. Ahearn and Hannay¹⁵ have studied the negative ions from SF_6 and find an F⁻ ion at 15.7 e.v. formed by an electron-pair process. They suggest that this appearance potential

Table II. Appearance Potentials of Selected Fragment Ions from S-NF and O-NF Compounds

Compound	Ion	A.P., e.v.	Assumed process
FSO ₂ NF ₂	FSO ₂ ⁺	13.1 ± 0.1	$FSO_2NF_2 \rightarrow FSO_2^+ + NF_2$
	NF_2^+	14.6 ± 0.3	$\rightarrow NF_2^+ + ?$
$(FSO_2)_2NF$	FSO_2^+	13.5 ± 0.1	$(FSO_2)_2NF \rightarrow FSO_2^+ + FSO_2NF$
SF ₅ NF ₂	$\mathbf{SF}_{\mathfrak{s}^+}$	14.3 ± 0.5	$SF_5NF_2 \rightarrow SF_5^+ + ?$
	SF ⁵⁺	12.0 ± 0.2	\rightarrow SF ₆ ⁺ + ?
	SF4 ⁺	15.9 ± 0.2	\rightarrow SF ₄ ⁺ + NF ₃
	SF ₃ +	16.0 ± 0.2	\rightarrow SF ₃ ⁺ + NF ₂ + F ₂
	\mathbf{NF}_2	16.3 ± 0.2	$\rightarrow NF_{2^{+}} + SF_{4} + F$
FSO ₂ ONF ₂	$\mathbf{NF_{2}^{+}}$	13.3 ± 0.1	$FSO_2ONF_2 \rightarrow NF_2^+ + FSO_2O$
	FSO_2^+	13.3 ± 0.2	\rightarrow FSO ₂ ⁺ + NO + F ₂

Table III. Bond Dissociation Energies in S-N and O-NF Compounds

Com- pound	Bond	D, kcal./ mole	$\Delta H_{f},$ kcal./ mole
FSO ₂ NF ₂	S–N	39	$-170 \pm 10^{\circ}$
(FSO ₂) ₂ NF	S-N	48	
SF ₅ NF ₂	S–N	32	-249 ± 10
FSO ₂ ONF ₂	O-N	35	-163 ± 10
FSO ₂ ONF ₂	S–O	~65	-163 ± 10

^a Estimated uncertainty in the heats of formation.

The bond energies and heats of formation (Table III) were calculated from the measured appearance

value is close to that of SF_5^+ reported by Diebler and Mohler¹² so that the process may be

$$SF_6 \longrightarrow SF_5^+ + F^-$$

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Using D(S-F) = 3.1 e.v. and the electron affinity of fluorine, E.A.(F) = 3.62 e.v., ¹⁶ I.P.(SF₅) = 15.4 e.v.is calculated. If this value for $I.P.(SF_5)$ is used, then a reasonable process cannot be written for the appearance potential of SF_5^+ from SF_5NF_2 .

The O-N bond dissociation energy for FSO₂ONF₂ was calculated to be 35 kcal./mole using I.P.(NF₂) and A.P.(NF₂⁺). Cottrell¹⁷ gives a range varying between 35 and 40 kcal./mole for the bond dissociation energy for alkyl nitrates and nitrites obtained by pyrolysis. The D(O-N) value found in this research is in good agreement with those results. The sulfuroxygen bond dissociation energy for FSO₂ONF₂

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was found to be ca. 65 kcal./mole from measurement of the appearance potential for the FSO_2^+ ion.

The substitution of fluorine atoms for other groups bonded to sulfur and/or nitrogen decreases the D(S-N)value. For the series, (FSO₂)₂NF, FSO₂NF₂, and SF_5NF_2 , there is a successive decrease in the D(S-N)values (Table III). This decrease might be expected owing to the electron-withdrawing power of the fluorine atoms. In addition, the low S-N bond dissociation energy value for SF_5NF_2 is consistent with its chemical behavior.4

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